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NFORMATION DISCLOSURE STATEMENT BY APPLICANT ( Not for submission under 37 CFR 1.99)

Application Number		10766768				
Filing Date		2004-01-27				
First Named Inventor	Rona	ald Duane McCallister	<del></del>			
Art Unit						
Examiner Name Baya		ard, Emmanuel	7			
Attorney Docket Number		2298-010				

	U.S.PATENTS										
Examiner Initial*	Cite No			Issue Date	Name of Patentee or Applicant of cited Document	Pages,Columns,Lines where Relevant Passages or Relevant Figures Appear					
·	1	4085378		1978-04-18	Ryan, et al.						
	2	5105445	А	1992-04-14	Karam, et al.						
	3	5819165	А	1998-10-06	Hulkko, et al.						
	4	5903823	A	1999-05-11	Moriyama, et al.						
	5	6081158	А	2000-06-27	Twitchell, et al.						
	6	6112059	А	2000-08-29	Schwent, et al.						
	7	6125266	<b>A</b>	2000-09-26	Matero, et al.						
	8	6133789	A	2000-10-17	Braithwaite						

( Not for submission under 37 CFR 1.99)

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9	6166601	A	2000-12-26	Shalom, et al.
10	6281936	B1	2001-08-28	Twitchell, et al.
11	6285412	B1	2001-09-04	Twitchell
12	6298097	B1	2001-10-02	Shalom
13	6335767	B1	2002-01-01	Twitchell, et al.
14	6337599	B2	2002-01-08	Lee
15	6507731	B1	2003-01-14	Hasegawa
16	6515712	B1	2003-02-04	Jeong
17	6600516	B1	2003-07-29	Danielsons, et al.
18	6775330	B2	2004-08-10	Bach, et al.
19	6794939	B2	2004-09-21	Kim, et al.

(Not for submission under 37 CFR 1.99)

		<del></del>				
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	20	6819720	B1	2004-11-16	Willetts	
	21	6856191	B2	2005-02-15	Bartuni	
·	22	7024608	B2	2006-04-04	Kurokami	

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### **U.S.PATENT APPLICATION PUBLICATIONS**

Examiner Initial*	Cite No	Publication Number	Kind Code <sup>1</sup>	Publication Date	Name of Patentee or Applicant of cited Document	Pages,Columns,Lines where Relevant Passages or Relevant Figures Appear
	1	20020090915	A1	2002-07-11	Komara, et al.	
	2	20020101937	A1	2002-08-01	Antonio, et al.	
	3	20030016741	A1	2008-04-10	Sasson, et al.	
	4	20030058959	A1	2003-03-27	Rafie, et al.	
	5	20030174783	A1	2003-09-18	Rahman, et al.	
	6	20030223508	A1	2003-12-04	Ding, et al.	·

#### Application Number 10766768 Filing Date 2004-01-27 INFORMATION DISCLOSURE First Named Inventor Ronald Duane McCallister STATEMENT BY APPLICANT Art Unit ( Not for submission under 37 CFR 1.99) Examiner Name Bayard, Emmanuel Attorney Docket Number 2298-010 7 20040164791 Α1 2004-08-26 Batruni 8 20040208242 Α1 2004-10-21 Batruni 9 20050101269 Α1 2005-05-12 Dale, et al. 10 20050123066 Α1 2005-06-09 Sarca If you wish to add additional U.S. Published Application citation information please click the Add button. **FOREIGN PATENT DOCUMENTS** Pages, Columns, Lines Name of Patentee or Examiner Cite Foreign Document Country Publication Kind where Relevant Passages or Relevant Applicant of cited Initial\* No Number<sup>3</sup> Code<sup>2</sup> j Code4 Date Document Figures Appear

						· · · · · · · · · · · · · · · · · · ·							
	1	1318643	EP	A1	2003-11-06	Kehlenbach, et al.							
If you wish	n to a	dd additional Foreign P	atent Document	citation	information pl	ease click the Add button	<u> </u>	1					
			NON-PATE	NT LITE	RATURE DO	CUMENTS							
Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.											
	1	CAVERS, "The Effect of Linearization" IEEE Tran	CAVERS, "The Effect of Quadrature Modulator and Demodulator Errors on Adaptive Digital Predistorters for Amplifier Linearization" IEEE Trans on Veh Tech, Vol46, #2, 05/97.										
	2	DING & ZHOU, "Effects of Even-order Nonlinear Terms on Power Amplifier Modeling and Predistortion Linearization" IEEE Transactions on Vehicular Technology, 08/2002.											
·													

( Not for submission under 37 CFR 1.99)

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First Named Inventor	Ron	ald Duane McCallister	
Art Unit			
Examiner Name Bay		ard, Emmanuel	
Attorney Docket Number		2298-010	

3	GRASS, BODHISATYA & MAHARATNA, "A Dual-Mode Synchornous/Asynchronous CORDIC Processor" IHP, IM Technologiepark, 2002.	
4	OHLSSON, "Studies on Implementation of Digital Filters With High Throughput and Low Power Consumption" Institute of Technology, Dept of Electrical Engineering, p 61-73, 06/03.	
5	RAICH, QIAN & ZHOU, "Digital Baseband Predistortion of Nonlinear Power Amplifiers Using Orthogonal Polynomials" Proc. ICASSP 2003, p 689-692, Hong Kong China, 04/2003.	
6	GODAVARTI, "Multiple Antennas in Wireless Communications" Array Signal Processing and Channel Capacity" University of Michigan, P 16-52, 2001.	
7	CHOO, "Mapping LMS Adaptive Filter IP Core to Multiplier-Array FPGA Architecture for High Channel-Density VOIP Line Echo Cancellation" CMP United Business Media, 2003.	
8	WIDROW, MCCOOL & BALL, "The Complex LMS Algorithm" Information Systems Laboratory, Naval Undersea Center, Fleet Engineering Dept, 08/19/1974.	
9	GLENTIS, KOUKOULAS, & KALOUPTSIDIS, "Efficient Algorithms for Volterra System Identification" IEEE Transactions on Signal Processing, Vol 47, No. 11, Nov 1999.	
10	DING, RAICH, & ZHOU, "A Hammerstein Predistortion Linearization Design Based on the Indirect Learning Architecture" in Proc. IEEE Intl. Conf. Acoust., Speech, Signal Processing, vol. 3, Orlando, FL, May 2002, pp. 2689-2692.	
11	RAZZAGHI & CHANG, "A 10-b,1GSample/s ADC using SiGe BiCMOS Technology" Proceedings of the Custom Integrated Circuits Conference (CICC), 433-436 (September 2003) San Jose, CA.	
12	DANESHRAD, "DSP VLSI Engine for Electronic Linearization of Fiber Optic Links" Wireless Integrated Systems Research Group, UCLA, 02/27/2001.	
13	IBANEZ-DIAZ, PANTALEON, SANTAMARIA, FERNANDEZ & MARTINEZ, "Nonlinearity Estimation in Power Amplifiers Based on Subsampled Temporal Data", IEEE 2001.	

( Not for submission under 37 CFR 1.99)

Application Number		10766768					
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Attorney Docket Numb	er	2298-010					

	,	<del></del>											
	14	EDMUND COERSMEIER & ERNST ZIELINSKI, "Frequency Selective IQ Phase and IQ Amplitude Imbalance Adjustments for OFDM Direct Conversion Transmitters", Mar. 2003.											
	15	SANTA from Su	SANTAMARIA, IBANEZ, LAZARO, PANTALEON & VIELVA, "Modeling Nonlinear Power Amplifiers in OFDM Systems from Subsampled Data: A Comparative Study Using Real Measurements", 2003.									; 	
	EUN, POWERS, "A New Volterra Predistortion Based on the Indirect Learning Architecture", 1997 IEEE.												
	17	PARK, WOO, RAICH, KENNEY & ZHOU, "Adaptive Predistortion Linearization of RF Power Amplifiers Using Lookup Tables Generated from Subsampled Data", IEEE 2002.											
	18	MORG/ Laborat	AN & MA, "Re tories, IEEE 20	ducing Mea 103.	sureme	nt Noise	Effects i	n Digital Pre	edistor	ion of RF Po	wer a	Amplifiers", Bell	
If you wis	h to a	dd additi	ional non-pat	ent literatu	re doc	ument c	itation i	nformation	pleas	e click the A	\dd	button	
		_			E	XAMINI	ER SIG	NATURE			-		
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Standard ST	F.3). 3 F cument	or Japane by the app	ese patent docu propriate symbo	nents, the in	dication of	of the vea	r of the re	ian of the Em	nperor n	nust precede ti	he se	ent, by the two-letter code (V rial number of the patent do cant is to place a check man	cument I